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FORM PTO 1449 (modified)				ATTY DOCKET NO. 862.C2217	APPLICATION NO. 09/845,297		
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				FILING DATE May 1, 2001		GROUP 2851	
		, ,	ET 1 5 2001 (E)	U.S. PATENT DOCUMENTS			
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AM	۷.	11-072607	03/16/1999	Japan			Abstract
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Aŋ	1	Flanders, D.C. and Henry I. Smith. "A new interferometric alignment technique," <i>Appli d Physics Letters</i> , Vol. 31, No. 7, October 1997. Pp. 426-428.					
AM	1	Roychoudhuri, C. "Chapter 6: Multiple-Beam Interferometers," Optical Shop Testing, Second Edition, Ed. by Daniel Malacara, John Wiley & Sons: 1992. Pp. 207-245.					
EXAMINER DATE CONSIDERED 1-11-2002							

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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